Preferred Device

# **Silicon Controlled Rectifiers**

# **Reverse Blocking Thyristors**

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

#### **Features**

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and Holding Characteristics
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Human Body Model, 3B > 8000 V Machine Model, C > 400 V
- Pb-Free Packages are Available

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) (T <sub>J</sub> = -40 to 125°C, Sine Wave, 50 to 60 Hz, Gate Open)  MCR12DCM  MCR12DCN	V <sub>DRM,</sub> V <sub>RRM</sub>	600 800	V
On–State RMS Current (180° Conduction Angles; T <sub>C</sub> = 90°C)	I <sub>T(RMS)</sub>	12	Α
Average On–State Current (180° Conduction Angles; T <sub>C</sub> = 90°C)	I <sub>T(AV)</sub>	7.8	Α
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T <sub>J</sub> = 125°C)	I <sub>TSM</sub>	100	Α
Circuit Fusing Consideration (t = 8.3 msec)	l <sup>2</sup> t	41	A <sup>2</sup> sec
Forward Peak Gate Power (Pulse Width $\leq$ 1.0 $\mu$ sec, T <sub>C</sub> = 90°C)	P <sub>GM</sub>	5.0	W
Forward Average Gate Power (t = 8.3 msec, T <sub>C</sub> = 90°C)	P <sub>G(AV)</sub>	0.5	W
Forward Peak Gate Current (Pulse Width $\leq$ 1.0 $\mu$ sec, $T_C$ = 90°C)	I <sub>GM</sub>	2.0	Α
Operating Junction Temperature Range	$T_J$	-40 to 125	°C
Storage Temperature Range	T <sub>stg</sub>	-40 to 150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. V<sub>DRM</sub> for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the device are exceeded.



## ON Semiconductor®

http://onsemi.com

# SCRs 12 AMPERES RMS 600 – 800 VOLTS





DPAK CASE 369C STYLE 4

## **MARKING DIAGRAM**



PIN ASSIGNMENT				
1	Cathode			
2	Anode			
3	Gate			
4	Anode			

#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

**Preferred** devices are recommended choices for future use and best overall value.

#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance - Junction-to-Case - Junction-to-Ambient - Junction-to-Ambient (Note 2)	$egin{aligned} R_{ hetaJC} \ R_{ hetaJA} \ R_{ hetaJA} \end{aligned}$	2.2 88 80	°C/W
Maximum Lead Temperature for Soldering Purposes (Note 3)	TL	260	°C

Characteristic	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS						
Peak Repetitive Forward or Reverse Blocking Current $(V_{AK} = Rated V_{DRM} \text{ or } V_{RRM}, \text{ Gate Open})$	T <sub>J</sub> = 25°C T <sub>J</sub> = 125°C	I <sub>DRM,</sub> I <sub>RRM</sub>	- -	_ _	0.01 5.0	mA
ON CHARACTERISTICS						
Peak Forward On–State Voltage (Note 4) (I <sub>TM</sub> = 20 A)		$V_{TM}$	-	1.3	1.9	V
Gate Trigger Current (Continuous dc) $(V_D = 12 \text{ V}, R_L = 100 \Omega)$	$T_{J} = 25^{\circ}C$ $T_{J} = -40^{\circ}C$	I <sub>GT</sub>	2.0	7.0 –	20 40	mA
Gate Trigger Voltage (Continuous dc) $(V_D = 12 \text{ V}, R_L = 100 \Omega)$	$T_{J} = 25^{\circ}C$ $T_{J} = -40^{\circ}C$	V <sub>GT</sub>	0.5 -	0.65 -	1.0 2.0	V
Gate Non–Trigger Voltage $(V_D = 12 \text{ V}, R_L = 100 \Omega)$	T <sub>J</sub> = 125°C	$V_{\sf GD}$	0.2	-	-	V
Holding Current (V <sub>D</sub> = 12 V, Initiating Current = 200 mA, Gate Open)	$T_{J} = 25^{\circ}C$ $T_{J} = -40^{\circ}C$	lн	4.0	22 -	40 80	mA
Latching Current $(V_D = 12 \text{ V}, I_G = 20 \text{ mA}, T_J = 25^{\circ}\text{C})$ $(V_D = 12 \text{ V}, I_G = 40 \text{ mA}, T_J = -40^{\circ}\text{C})$		lι	4.0	22 -	40 80	mA
DYNAMIC CHARACTERISTICS				•		
Critical Rate of Rise of Off–State Voltage (V <sub>D</sub> = Rated V <sub>DRM</sub> , Exponential Waveform, Gate Open, T <sub>J</sub> = 125°C)		dv/dt	50	200	-	V/μs

<sup>2.</sup> These ratings are applicable when surface mounted on the minimum pad sizes recommended.

## **ORDERING INFORMATION**

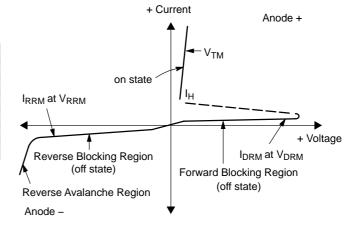
Device	Package	Shipping <sup>†</sup>
MCR12DCMT4	DPAK	2500 / Tape and Reel
MCR12DCMT4G	DPAK (Pb-Free)	2500 / Tape and Reel
MCR12DCNT4	DPAK	2500 / Tape and Reel
MCR12DCNT4G	DPAK (Pb-Free)	2500 / Tape and Reel

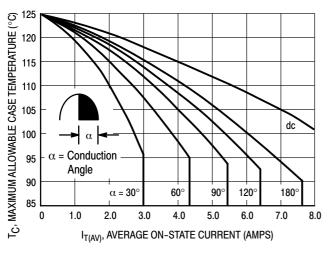
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

 <sup>1/8&</sup>quot; from case for 10 seconds.
 Pulse Test: Pulse Width ≤ 2.0 msec, Duty Cycle ≤ 2%.

## **Voltage Current Characteristic of SCR**

Symbol	Parameter
V <sub>DRM</sub>	Peak Repetitive Off-State Forward Voltage
I <sub>DRM</sub>	Peak Forward Blocking Current
V <sub>RRM</sub>	Peak Repetitive Off-State Reverse Voltage
I <sub>RRM</sub>	Peak Reverse Blocking Current
$V_{TM}$	Peak On–State Voltage
IH	Holding Current

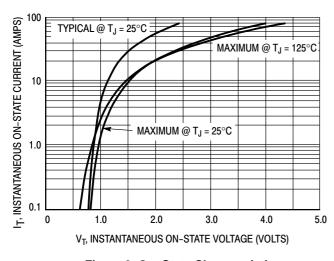




P(AV), AVERAGE POWER DISSIPATION (WATTS) 180° 120° 90° 12 60° dc  $\alpha$  = Conduction 10 Angle 8.0  $\alpha = 30^{\circ}$ 6.0 4.0 2.0 1.0 7.0 8.0  $I_{T(AV)}$ , AVERAGE ON-STATE CURRENT (AMPS)

Figure 1. Average Current Derating

Figure 2. On-State Power Dissipation



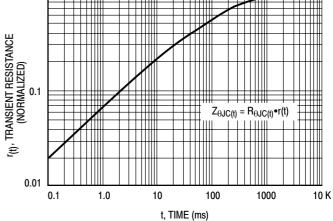


Figure 3. On-State Characteristics

Figure 4. Transient Thermal Response

1.0

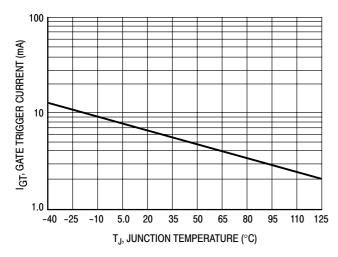


Figure 5. Typical Gate Trigger Current versus Junction Temperature

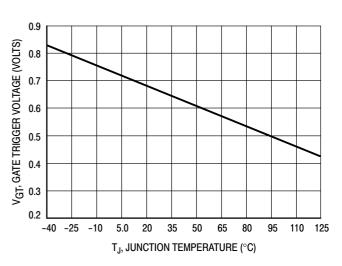


Figure 6. Typical Gate Trigger Voltage versus
Junction Temperature

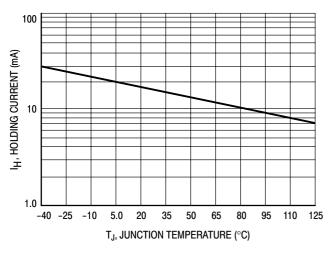


Figure 7. Typical Holding Current versus Junction Temperature

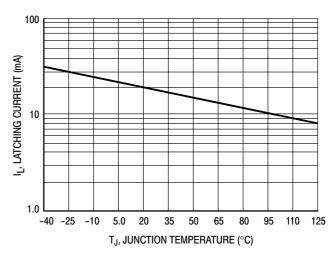


Figure 8. Typical Latching Current versus Junction Temperature

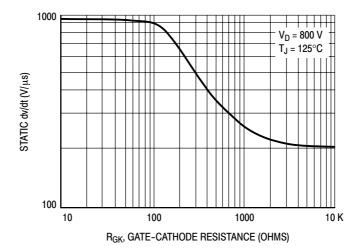
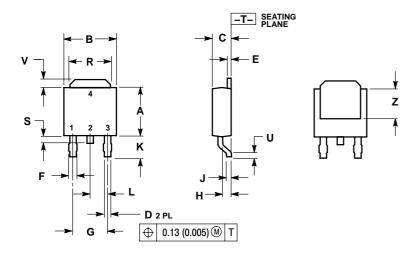


Figure 9. Exponential Static dv/dt versus Gate-Cathode Resistance

#### PACKAGE DIMENSIONS

#### DPAK CASE 369C ISSUE O



#### NOTES:

- DIMENSIONING AND TOLERANCING
   PER ANSI Y14.5M. 1982.
- 2. CONTROLLING DIMENSION: INCH.

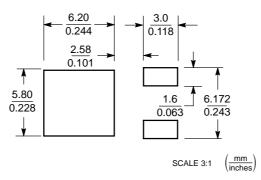
	INCHES		MILL IN	ETEDE
			MILLIMETER	
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.22
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.180 BSC		4.58 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.102	0.114	2.60	2.89
L	0.090 BSC		2.29 BSC	
R	0.180	0.215	4.57	5.45
S	0.025	0.040	0.63	1.01
U	0.020		0.51	
٧	0.035	0.050	0.89	1.27
Z	0.155		3 93	

STYLE 4:

PIN 1. CATHODE 2. ANODE

- 3. GATE
- 4. ANODE

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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